

文章编号: 1001-3806(2006)04-0340-04

基于最大色差彩色组合编码的三维面形测量方法

朱清溢, 苏显渝*, 肖焱山, 向立群

(四川大学 电子信息学院 光电系, 成都 610064)

摘要: 为了克服光学三维传感中相位恢复困难的问题, 提出了一种基于最大色差彩色组合编码的三维面形测量方法。这种方法的特点之一是使得垂直于条纹方向特定长度的颜色序列是唯一的, 从而建立了空间位置与颜色的对应关系。特点之二是相邻条纹之间具有最大色差, 因而具有最大可区分性。将得到的彩色组合条纹投影到物体表面得到变形条纹, 通过计算各种颜色条纹相对参考平面上条纹移动的距离, 可以恢复出物体的高度。实验证明, 该方法需要获取的图像少、计算时间少、精度较高, 具有很强的抗干扰能力。

关键词: 信息光学; 三维轮廓术; 彩色编码结构光; 边界提取; 高度映射表

中图分类号: O438 **文献标识码:** A

3-D shape measurement method with max-difference color-coding structured light

ZHU Qing-yi, SU Xian-yu, XIAO Yan-shan, XIANG Li-qun

(Department of Opto-Electronics Science & Technology, School of Electronics & Information Technology, Sichuan University, Chengdu 610064, China)

Abstract: A 3-D shape measurement method using max-difference color-coding structured light is suggested to avoid complicated phase-recover process in three-dimension sensing. A pattern of exclusive color sequence is obtained and a relationship between spatial location and color is established. The difference of neighboring colors is maximized so that they can be distinguished easily. Projecting the color-combination fringe to the object and reference plane respectively, two images are taken. The height of the object can be recovered by edge detection and triangulation. This method has been implemented and proved to be fast, precise and noise-immune.

Key words: information optics; 3-D shape measurement; color-coding structured light; edge detection; height look-up table

引 言

光学三维轮廓测量在三维传感、机器视觉、工业检测、生物医学等方面有着广泛的应用^[1~3]。基于相位测量的三维轮廓术是光学三维测量的重要方法^[4,5]。相位测量轮廓术 (phase measuring profilometry, PMP) 采用正弦光栅投影和数字相移技术, 只需要 3 幅或更多图像即可从强度图像中解出相位函数, 从而得到物体的高度, 这种方法具有较高的精度, 是一种普遍采用的方法。能否正确恢复出原始相位是该方法的关键问题, 由于求解过程中使用了反三角函数, 使求解出来的相位函数截断在 $(-\pi, \pi)$ 主值范围内, 并且实际条纹图形中可能存在阴影、断裂以及相邻抽样点之间相位大于 π 等问题, 使原始相位的恢复变得非常困难。另外, 该方法处理的相位是连续变化的模拟量, 容易受投

影仪与摄像装置的随机噪声以及物体表面灰度的影响, 多帧相移图像的获取影响测量速度, 使这种方法也受到一定的局限。

针对以上问题, 人们提出了很多方法, 比如用颜色来携带物体的三维信息。CASPI 等^[6]提出用可调整彩色结构光来测量距离, 根据场景的不同改变投影条纹的形状和数量, 使需要投影的条纹图最少。YEH 等^[7]通过编码得到颜色序列, 利用颜色序列的唯一性来确定颜色和高度对应关系。HUANG 等^[8]提出用连续光谱结构光和条纹状结构光取代正弦光栅。LU 等^[9,10]将数字化技术运用于投影光栅编码中, 提出了两位数字编码方案、彩色组合编码方案以及链式编码方案。作者提出一种相邻码间具有最大色差的彩色组合编码方案, 得到不同的颜色序列, 并将这些颜色沿一维方向进行编码, 建立空间位置与颜色的对应关系, 取代相位测量轮廓术中相位与高度的对应关系。文中提出了一种基于 RGB 空间距离大小的边界提取算法对变形条纹提取边界, 这种算法利用了所设计的最大色差彩色组合编码方案, 具有较高的可靠性。作者详细

作者简介: 朱清溢 (1976-), 男, 硕士研究生, 主要从事三维传感方面的工作。

* 通讯联系人。E-mail: xysu@email.scu.edu.cn

收稿日期: 2005-06-14; 收到修改稿日期: 2006-03-06

论述了编码、解码、边界提取以及高度计算的原理和算法,并且进行了实验论证。

1 原理

1.1 选色与编码,分色与解码

在 RGB 彩色模型中,每个点的像素值由 r, g, b 3 个分量组成。作者对这 3 个分量进行二值化处理,分别取 0 和 1 两种状态,通过组合,一共可以得到 8 种颜色(见表 1)。这 8 种颜色分别位于 RGB 彩色立方体的 8 个顶点,从而保证了任意两个点之间的距离很大,使用这些颜色进行编码,使得相邻条纹的颜色差异很大,有利于边界提取。

Table 1 Color choosing

color	r value	g value	b value	expression
red	1	0	0	(1, 0, 0)
green	0	1	0	(0, 1, 0)
blue	0	0	1	(0, 0, 1)
cyan	0	1	1	(0, 1, 1)
magenta	1	0	1	(1, 0, 1)
yellow	1	1	0	(1, 1, 0)
white	1	1	1	(1, 1, 1)
black	0	0	0	(0, 0, 0)

可以根据需要,从这 8 种颜色中取出几种来进行编码。编码过程中,需要考虑以下问题:(1)投影系统的分辨率。假如投影系统在编码方向的分辨率为 600,设计每个条纹占 6 个像素,则只需要 100 个条纹;(2)背景和物体的颜色。尽量不要选用和背景或物体相近的颜色进行编码,以便区分物体、背景和条纹;(3)相邻两个条纹的颜色不能重复,并且从条纹任意位置取连续的 5 个条纹,其颜色序列是唯一的,即相同的颜色序列在条纹中不能重复出现。这是编码的关键,只有颜色序列的唯一性才能保证颜色和空间位置的一一对应关系。故投影系统的分辨率越高,需要的条纹数也越多,为了保证颜色序列的唯一性,编码时需要用到的颜色也越多。假如有 5 种颜色进行编码,为了保证颜色序列的唯一性以及相邻条纹不重复,根据排列组合原理,理论上一共有 $5 \times 4 \times 4 \times 4 \times 4 = 1280$ 个颜色序列,每个序列有 5 个条纹,假设每个条纹宽度为 5 个像素,则编码长度可以达到 $1280 \times 5 \times 5 = 32000$ 个像素,远远超过了常用投影系统的分辨率。

当条纹投影到物体表面时,条纹颜色会被物体颜色影响,为此,设计了一套有效的分色流程(见图 1),通过阈值 T 的设置,可以达到良好的分色效果。其中黑色为无效区域,它的高度通过插值得到。该流程可以处理 8 种颜色,当编码颜色减少时,流程可以得到相应的简化。

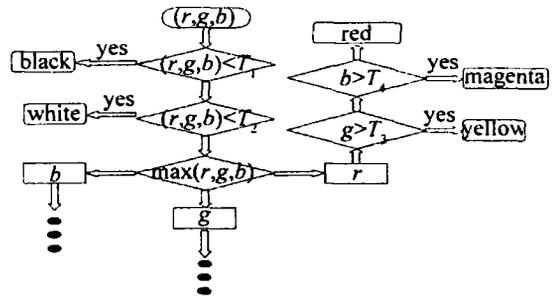


Fig 1 Color classification rule

解码过程中,从条纹任意位置读取 1 个条纹,再依次往后读取 4 个条纹,组成一个长度为 5 的颜色序列,将此颜色序列与已知的颜色序列比较,可以找出它在原始序列中的位置,从而确定该条纹在整个条纹图中的位置。

1.2 边界提取

在 RGB 彩色空间中,假如有 $A(r_1, g_1, b_1), B(r_2, g_2, b_2)$ 两点,将这两点的距离定义为:

$$D = \sqrt{(r_2 - r_1)^2 + (g_2 - g_1)^2 + (b_2 - b_1)^2} \quad (1)$$

使用(1)式,逐列(如果条纹是竖直的则逐行)计算条纹图中相邻两点的距离,可以得到 1 个距离矩阵。该矩阵中,在同一个条纹内部,由于颜色是一致的,其距离近似等于 0;在条纹边界,由于颜色的跃变,其距离远大于 0。通过寻找距离矩阵的峰值,就可以确定条纹边界的位置。实际处理时,需要先使用低通滤波器去除噪声。

1.3 系统标定与高度映射表的建立

条纹边界走过的轨迹在空间形成一系列的平面。同时,摄像系统光心与像平面上任一点组成一个向量。这些平面方程以及向量方程可以通过系统标定来得到。某个向量以及它对应的平面方程的交点就是物体上的某一点。当已知平面方程以及向量方程,可以很方便地求出该点的坐标。

建立平面及向量方程的时候,需要知道系统的几何参数。准确地测量这些参数比较复杂,为了避免测量这些参数,建立了高度映射表。将条纹投影到参考平面上,参考平面等距离地移动至 6 个不同的位置,相邻位置间隔 20mm,可以得到不同高度的条纹图。图 2 为其中的一幅。提取这些条纹图的边界,就可以确定不同颜色条纹的位置。把相同颜色条纹的各个位置组

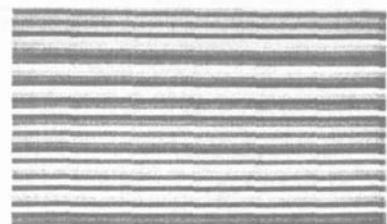


Fig 2 Image taken from the reference plane

合在一起,就可以得到高度映射表。它包括两方面信息:一是位置信息,二是颜色序列。表 2为高度映射表的一部分。实际测量过程中,确定了某个条纹的颜色代码和位置以后,通过插值就可以得到物体的高度。

Table 2 Part of height look-up table

color	0mm	20mm	40mm	60mm	80mm	100mm
red	218.3	229.4	240.9	253.3	266.0	279.3
blue	232.5	243.6	255.1	267.5	280.2	293.7
white	247.3	258.4	270.0	282.4	295.1	308.4
red	261.7	272.8	284.4	296.6	309.6	323.0
blue	276.9	288.1	299.8	312.1	324.7	337.9
green	290.3	301.5	313.0	325.5	338.2	351.8
blue	305.3	316.7	328.3	340.5	353.0	366.3
green	320.5	331.6	343.0	355.5	368.4	381.5
blue	334.5	346.0	357.6	370.0	382.7	395.8
red	348.7	359.7	371.4	383.5	396.4	409.8
white	363.1	374.2	386.0	398.3	410.8	424.4

2 实验

采用上述方法,对头像模型进行了实验。图 3为实验装置图。彩色 CCD的分辨率为 576 × 704。投影

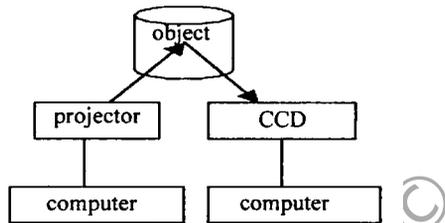


Fig 3 System structure

仪在编码方向的分辨为 600 像素,设计每个条纹占 8 个像素,所以一共需要 75 个条纹。为此,选用红,绿,蓝三原色以及白色 4 种颜色进行编码,由 1.1 节可知,一共有 $4 \times 3 \times 3 \times 3 \times 5 = 1620$ 个条纹,远远大于需求。图 4为编码后的条纹图,其中每个条纹的位置是确定的。通过数字投影仪将该条纹投影到物体表面,在与投影仪偏离一定角度的 CCD 中就可以拍摄到变形条纹。

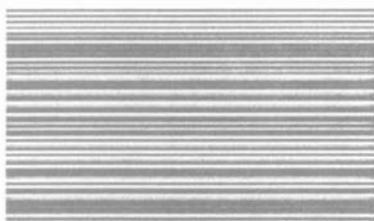


Fig 4 Encoded fringe

拍摄了两幅图像,一幅是受物体高度调制的变形条纹图,另一幅是白光均匀照明下的物体图像,分别表示为 $F(r, g, b)$ 和 $O(r, g, b)$ 。图 5为实验中获取的图像,其中图 5c为去背景后的变形条纹图,表示为 $F_1(r, g, b) = O(r, g, b) - F(r, g, b)$ 。

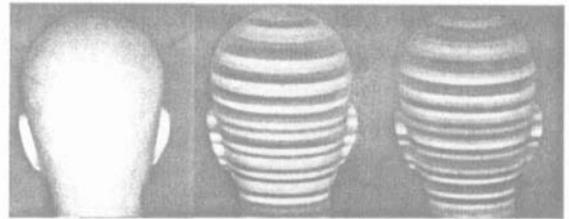


Fig 5 Images obtained from experiment

a—background b—deformed fringe c—background removed

采用 1.2 节中所示方法对 $F_1(r, g, b)$ 提取边界。先用一维低通滤波器对 $F_1(r, g, b)$ 的各个分量进行逐列滤波处理,去除噪声,得到 $F_2(r, g, b)$ 。再使用 (1) 式逐列计算 $F_2(r, g, b)$ 中相邻点在 RGB 彩色空间的距离,得到距离矩阵 $D(m, n)$ 。然后使用二维低通滤波器去除 $D(m, n)$ 的噪声,最后采用最大值滤波提取峰值,就可以得到边界矩阵 $E(m, n)$ 。整个边界处理的流程图见图 6。

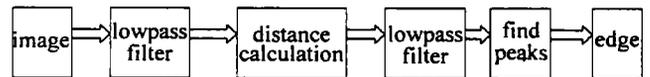


Fig 6 Flowchart of edge detection

图 7a为边界处理结果示意图,图 7b为距离矩阵 $D(m, n)$ 中的一列,此外,还需要采用 1.1 节中的方法对变形条纹图进行分色处理,与边界矩阵 $E(m, n)$ 对应,可以得到颜色矩阵 $C(m, n)$ 。

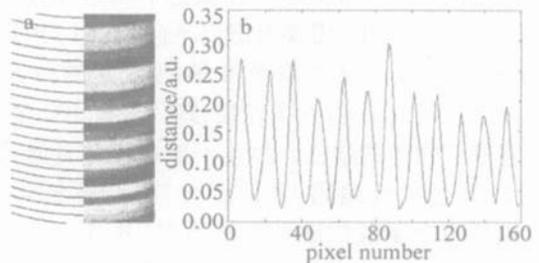


Fig 7 Results of edge detection

每隔 5 列扫描边界矩阵 $E(m, n)$,每遇到一个边界,在颜色矩阵 $C(m, n)$ 相应位置找到其颜色,再往后读取 4 个颜色,组成 1 个颜色序列。根据这个颜色序列在高度映射表中寻找相同的颜色序列,可以查出该条纹在不同高度的位置,通过插值就可以计算出该点的高度。其它位置的高度可以通过插值得到。重建后的物体如图 8 所示。从图 8 可以看出,物体顶部恢复效果比较好,而沿四周的底部与实物有一定差异,这是

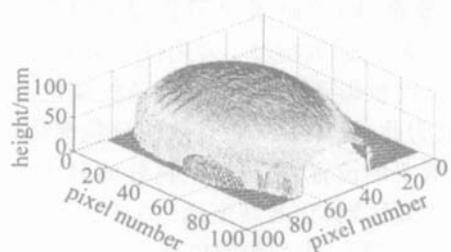


Fig 8 Reconstructed object

由于物体高度比较大,而 CCD 的景深不够,造成物体底部成像比较模糊,给边界提取带来困难,所以这个区域的高度只有通过插值来得到。

3 结 论

作者提出的彩色组合编码的三维面形测量方法具有两个特点,其一是使得垂直于条纹方向特定长度的颜色序列是唯一的,从而建立了空间位置与颜色的对应关系,其二是相邻条纹的组合具有最大色差,因而具有最大可区分性,易于提取彩色条纹的边界。实验证明,只需要获取两幅图像,就可以恢复出物体的形状。计算过程全部由计算机完成,边界提取是该方法的关键,边界检测的精度受数码相机分辨率,投影仪和摄像机的频谱响应特性和随机噪声等因素影响。如果采用高分辨的投影仪和摄像机,该方法可以获得较高的精度。

参 考 文 献

- [1] CHEN F, BROWN G M, SONG M. Overview of three dimensional shape measurement using optical methods [J]. *Opt Engng*, 2000, 39 (1): 10~22

(上接第 339 页)

干涉采样技术的采用,角振动将引入显著的相移误差,从而引起相位恢复误差,并进一步引起测量误差。相移与测量结果误差在很大程度上依赖于剪切量大小和角振动的幅度。当角振动幅度小于 0.001,且剪切量小于 0.82mm 时,测量结果误差将小于 0.004 μm 。

现有的精密表面加工设备,如 RANK PNEUMO OPTOFORM 300 单点钻石车床通常有好的振动环境,可满足研究的横向剪切干涉仪实现在线表面精密测量所允许的在线振动环境要求。

参 考 文 献

- [1] HARIHARAN P. Interferometric testing of optical surfaces: Absolute measurements of flatness [J]. *Opt Engng*, 1997, 36 (9): 2478~2481.
- [2] MALACARA D. *Optical shop testing* [M]. 2nd ed, New York: John Wiley & Sons Inc, 1992. 123~172.
- [3] EUGEN D G, FRNSM. Phase-shifting shearing interferometry with a variable polarization grating recorded on Bacteriorhodopsin [J]. *Opt Commun*, 2004, 241: 309~314.
- [4] LEIBRANDT G W R, HARBERS G, KUNST P J. Wave front analy-

- [2] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [3] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [4] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [5] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [6] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [7] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [8] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [9] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [10] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [11] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [12] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [13] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [14] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [15] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [16] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [17] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [18] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [19] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [20] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [21] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [22] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [23] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [24] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [25] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [26] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [27] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [28] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [29] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [30] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [31] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [32] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [33] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [34] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [35] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [36] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [37] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [38] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [39] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [40] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [41] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [42] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [43] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [44] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [45] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [46] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [47] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [48] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [49] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [50] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [51] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [52] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [53] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [54] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [55] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [56] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [57] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [58] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [59] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [60] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [61] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [62] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [63] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [64] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [65] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [66] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [67] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [68] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [69] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [70] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [71] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [72] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [73] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [74] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [75] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [76] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [77] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [78] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [79] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [80] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [81] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [82] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [83] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [84] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [85] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [86] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [87] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [88] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [89] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [90] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [91] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).
- [92] SU X Y, LIJ T. New development of 3-D shape measurement [J]. *Physics*, 1996, 25 (10): 614~620 (in Chinese).
- [93] DU L B, GAO X H, XIA J J *et al* Research of a novel 3-D laser scanning system [J]. *Laser Technology*, 2005, 29 (4): 366~369 (in Chinese).
- [94] SU X Y, von BALLY G, VUKICEVIC D. Phase stepping grating profilometry: utilization of intensity modulation analysis in complex objects evaluation [J]. *Opt Commun*, 1993, 98: 141~150.
- [95] ZHAO H, CHEN W Y, TAN Y Sh. A novel phase measuring profilometry [J]. *Acta Optica Sinica*, 1995, 15 (7): 898~901 (in Chinese).
- [96] CASPID, KRYATIN, SHAMIR J. Range imaging with adaptive color structured light [J]. *IEEE Transactions on Pattern Analysis and Machine Intelligence*, 1998, 20 (5): 470~480.
- [97] YEH Y H, CHANG I Ch, HUANG Ch L *et al* A new fast and high-resolution 3-D imaging system with color structured light [J]. *SPIE*, 2002, 4925: 645~654.
- [98] HUANG H Q, FENG H J, XU Zh H *et al* 3-D imaging base on color-encoded structure light [J]. *Journal of Zhejiang University (Engineering Science)*, 2001, 35 (6): 588~591 (in Chinese).
- [99] LIU W Y, WANG Zh Q. Three dimensional surface profilometry using binary system color-coded grating method [J]. *Journal of Optoelectronics · Laser*, 2000, 11 (2): 179~182 (in Chinese).
- [100] LIU W Y, WANG Zh Q, MU G G *et al* Color permutation coded grating profilometry [J]. *Acta Optica Sinica*, 2000, 20 (9): 1218~1223 (in Chinese).